## DUNE 35t Activity at BNL Status

B. Kirby- April 8, 2015 - BNL DUNE Local Meeting

## BNL EDG and the DUNE 35t Detector

- BNL EDG group tasked with testing DUNE 35t electronic production electronics
- Test board functionality, reliability at cryogenic temperature, measure performance
- Work with instrumentation dept to debug board and firmware issues
- Integrate frontend readout into 35 t DAQ
- Develop calibration and commissioning procedures
- Contribute to electronics simulation
- Current activity focused on board validation
- Significant delay in board production schedule
- Originally anticipated production boards in Oct.
- Received production boards end of Dec.
- Cryogenic testing started end of January, ongoing...


## Reminder: 35t FEMBs

- $35 t$ FrontEnd MotherBoards (FEMBs) contain analog board, FPGA board and ERNI interface board
- Analog board: 8 pairs of shaping-amplifier ASICs and digitizing ADC ASICs, 128 channels
- FPGA board: Programs and coordinates ASIC operation and readout, streams data to backend through GB transceivers and PGP interface
- ERNI connector board: GB cable connector board



## 35t FEMBs in the DAQ



- ArtDAQ provides run control, initiates configuration of subdetectors
- BoardReader receives formatted data from Cluster-on-Board (COB)
- COB receives FEMB data, sends FEMB configuration through SLAC PGP interface - Also applies zero-suppresion (to be implemented!)
- FEMBs fully integrated into DAQ as of March 20:
- FEMBs configured and ADC data streamed using artDAQ interface
- Have PGP-card readout working at BNL, emulates COB readout


## 35t Production Board Validation

 Procedure- Boards validated in several steps:
a. Basic functionality tests
- Verify boards work, can be calibrated
b. Cryogenic testing:
- Verify boards continue to work in liquid nitrogen, can be programmed, take data etc.
c. Final validation data-taking
- Determine if boards still work after cryo testing

35t FEMB Tested in Liquid Nitrogen


## Board Validation Status

| Overall FEMB Testing Summary |  | Current Location | Basic Test | Cryogenic Test | Final Modifications? | Valldation Data Runs | Valldation Data Analyzed? | Cleaned? | Shipped? |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| FEMB\# | Identifier |  |  |  |  |  |  |  |  |
|  |  |  | Test Log | Cryo Test Log |  | Run Log |  |  |  |
| 1 | F1A1E1 | Instrumentation | PASS | FAIL | - |  |  |  |  |
| 2 | F2A2E2 | Instrumentation | PASS | FAIL | - |  |  |  |  |
| 3 | F3A?E3?? | FNAL | MISSING | PASS | - |  |  |  |  |
| 4 | F4AAE4 | lab 233 | PASS | PASS | PASS | 433-469 |  | PASS |  |
| 5 | F5A5E5 | Instrumentation | PASS | FAIL | - |  |  |  |  |
| 6 | F6A6E6 | lab 233 | PASS | PASS | IN PROGRESS |  |  |  |  |
| 7 | F7ATET | Instrumentation | PASS | FAIL | - |  |  |  |  |
| 8 | F8ABE8 | FNAL | PASS | PASS | - |  |  |  |  |
| 9 | F9APE9 | lab 233 | PASS | PASS | PASS | 356-393 | PASS | PASS |  |
| 10 | F10A10E10 | lab 233 | PASS | PASS | PASS | 318-355 | PASS | PASS |  |
| 11 | F11A11E11 | lab 233 | PASS | PASS | REDO - needs P5 connector | 168-207 | PASS | PASS |  |
| 12 | F12A12E12 | Instrumentation | PASS | FAIL | - |  |  |  |  |
| 13 | F13A13E13 | lab 233 | PASS | PASS | PASS | - |  | PASS |  |
| 14 | F14A14E14 | high-bay | PASS | FAIL | - |  |  |  |  |
| 15 | F15A15E15 | lab 233 | PASS | PASS | IN PROGRESS |  |  |  |  |
| 16 | F16A16E16 | Instrumentation | PASS | FAIL | - |  |  |  |  |
| 17 | F17A17E17 | lab 233 | PASS | PASS | PASS | 394-430 | PASS | PASS |  |
| 18 | F18A18E18 | Instrumentation | PASS | MODIFIED-UNU | USABLE |  |  |  |  |
| 19 | F19A0E19 | high-bay | PASS | FAIL |  |  |  |  |  |

## Summary of Current Board Failures

- 3 boards not programmable by JTAG in liquid nitrogen
- Cause is not clear, swapping FPGA boards
- 3 boards have ASICs not getting programmed by SPI
- Usually single pin issue
- 1 boards not streaming data from all ASICs
- ADC link or FPGA board connector problem
- 1 ASIC not getting calibration signal
- ASIC replaced April 7


## "Stuck Code" Issue with FEMB Data

Example Baseline Waveform


ADC Sample Distribution Vs. Channel \#


- Still observe "stuck ADC codes" in FEMB digitized data
- Fairly rare at room temperature, $\sim 3 \%$ of channels
- Issue becomes worse in liquid nitrogen, see significant variation between boards
- Electronic noise or variation in ADC ASIC power supply possibly causes
- Under study by us and instrumentation dept engineer + student
- Baseline distribution obtained from entire FEMB shows interesting features
- Offsets possibly FE ASIC feature, does not affect pulse shapes
- Used low-threshold setting to make this plot, induction channels will be OK


## Summary

- Nearly finished validating $35 t$ production boards
- 8 boards being debugged
- Trying to understand ADC code issue in liquid nitrogen
- Running out of time to fix it in hardware
- Looking at firmware fixes (staggering ADC sampling clocks)
- Considering software fixes (spurious sample filter?)
- Critical that physicists help BNL engineers with next revision of cold electronic boards:
- Boards/ASICs redesign underway, informed from 35t issues
- Engineers have significant time constraints, need help analyzing large amount of data and boards
- Test setup in place for room temperature and cryogenic board testing going forward

